

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

| | | | |
|-------------|--|-----------------|------------|
| Applicant: | Bruce et al. | Examiner: | Turner, S. |
| Serial No.: | 09/386,112 | Group Art Unit: | 2877 |
| Filed: | August 30, 1999 | Docket No.: | AMDA.261PA |
| Title: | DUAL-DIFFERENTIAL INTERFEROMETRY FOR SILICON DEVICE DAMAGE DETECTION | | |

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence and the papers, as described hereinabove, are being transmitted via facsimile only-Formal Entry, to the attention of Examiner S. Turner, Assistant Commissioner for Patents, Washington, D.C. 20231, on October 28, 2002.

By: Eric J. Curtin

Facsimile No. (703) 872-9319

Eric J. Curtin

OFFICE ACTION RESPONSE AND AMENDMENT

BOX AF
Assistant Commissioner for Patents
Washington, D.C. 20231

FAX COPY RECEIVED

OCT 28 2002

Dear Sir:

TECHNOLOGY CENTER 2800

In response to the Office Action dated August 27, 2002, please consider the following remarks.

Remarks

Favorable reconsideration of this application is requested in view of the following remarks. For the reasons set forth below, Applicant respectfully submits that the claimed invention is allowable over the cited references.

The Office Action dated August 27, 2002 indicated that claims 1-16 stand rejected under Section 112(1); claims 1-16 stand rejected under Section 112(2); and claims 1, 2, 7, and 9-15 stand rejected under Section 103(a) as being unpatentable over *Marx et al.* (U.S. Patent No. 5,880,838).